

Application/Control No.	Applicant(s)/Patent under Reexamination OH, JEONG-HWAN	
10/525,130		
Examiner	Art Unit	
Charles Kim	2624	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
search updated (see search history report)	11/19/2007	ĊК		
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